Infineon Technologies - MB96F637RBPMC-GSE1 Datasheet

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What is "Embedded - Microcontrollers"?

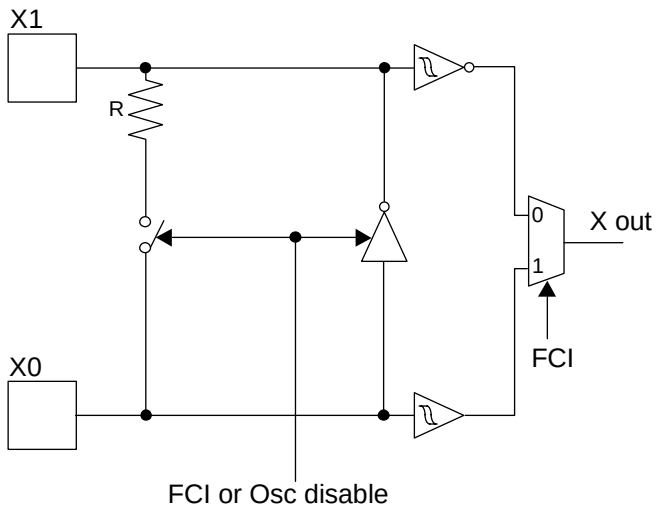
"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

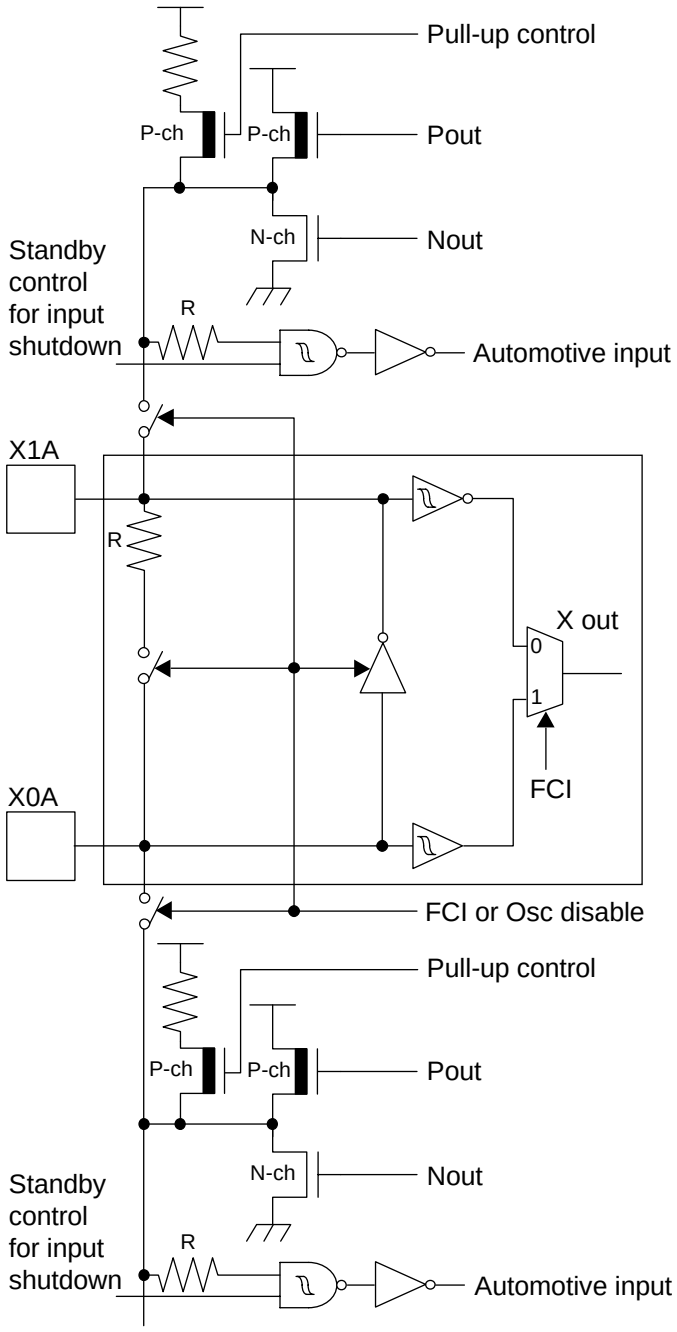
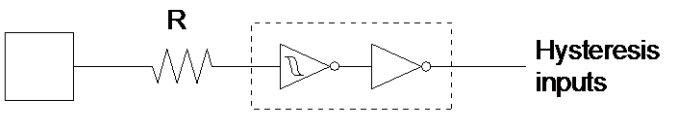
Applications of "Embedded - Microcontrollers"

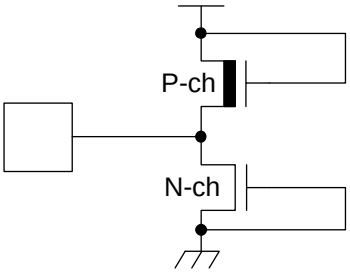
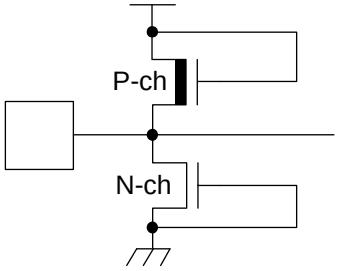
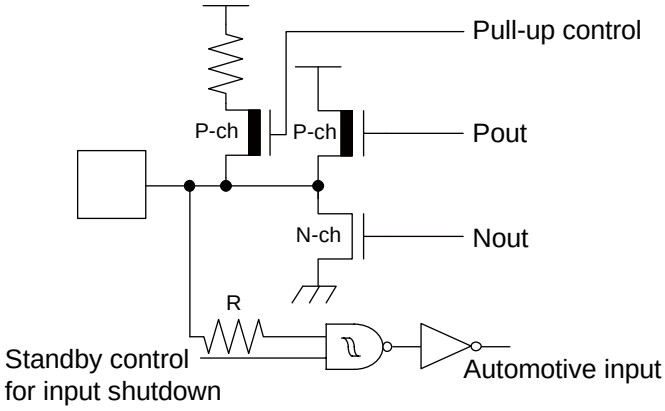
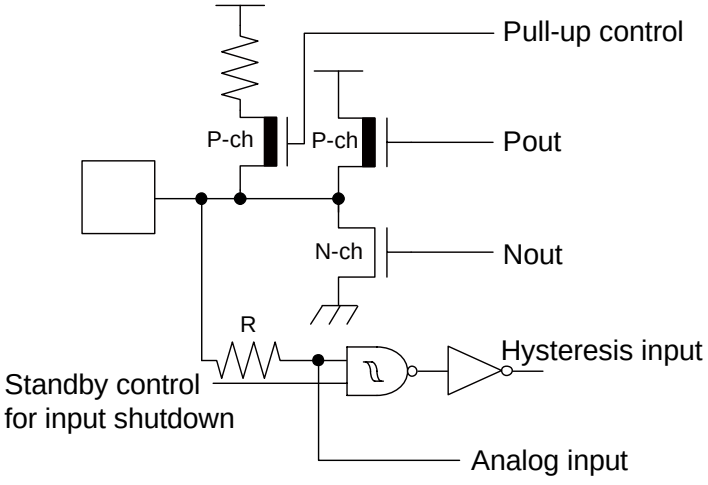
Details	
Product Status	Obsolete
Core Processor	F²MC-16FX
Core Size	16-Bit
Speed	32MHz
Connectivity	CANbus, I²C, LINbus, SCI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	64
Program Memory Size	416KB (416K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	28K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 21x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	80-LQFP
Supplier Device Package	80-LQFP (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb96f637rbpmc-gse1

Pin name	Feature	Description
TXn	CAN	CAN interface n TX output pin
Vcc	Supply	Power supply pin
Vss	Supply	Power supply pin
WOT	RTC	Real Time clock output pin
WOT_R	RTC	Relocated Real Time clock output pin
X0	Clock	Oscillator input pin
X0A	Clock	Subclock Oscillator input pin
X1	Clock	Oscillator output pin
X1A	Clock	Subclock Oscillator output pin
ZINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin

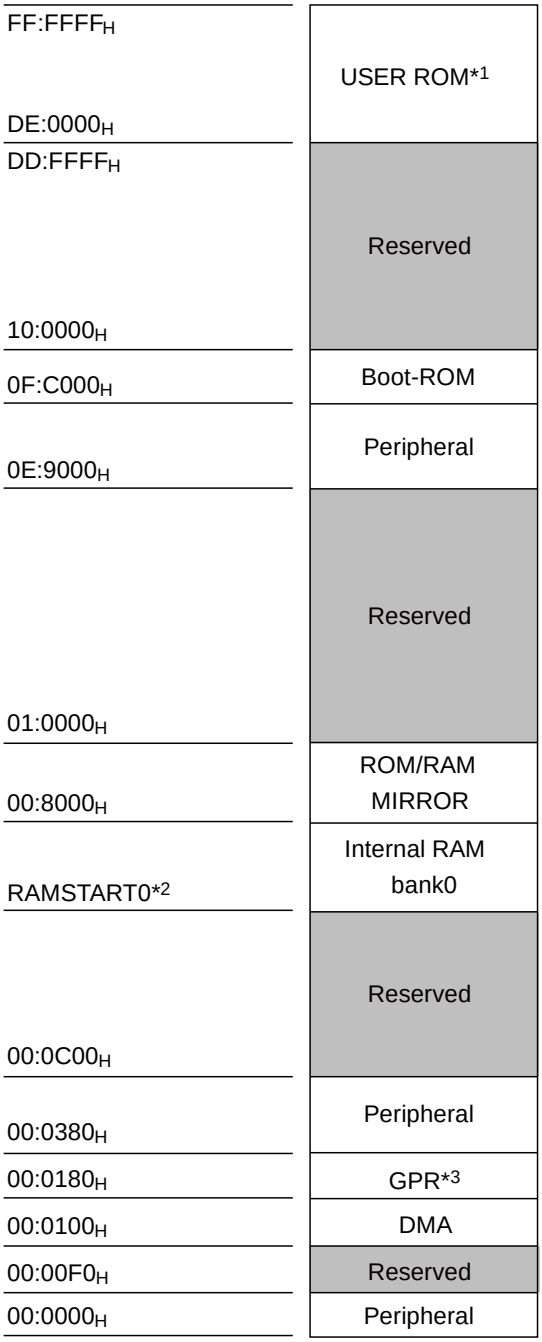
6. I/O Circuit Type

Type	Circuit	Remarks
A		High-speed oscillation circuit: • Programmable between oscillation mode (external crystal or resonator connected to X0/X1 pins) and Fast external Clock Input (FCI) mode (external clock connected to X0 pin) • Feedback resistor = approx. 1.0MΩ • The amplitude: 1.8V±0.15V to operate by the internal supply voltage

Type	Circuit	Remarks
B		Low-speed oscillation circuit shared with GPIO functionality: • Feedback resistor = approx. 5.0MΩ • GPIO functionality selectable (CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA), Automotive input with input shutdown function and programmable pull-up resistor)
C		CMOS hysteresis input pin

Type	Circuit	Remarks
F		Power supply input protection circuit
G		• A/D converter ref+ (AVRH) power supply input pin with protection circuit • Without protection circuit against V_{CC} for pins AVRH
H		• CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) • Automotive input with input shutdown function • Programmable pull-up resistor
I		• CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) • CMOS hysteresis input with input shutdown function • Programmable pull-up resistor • Analog input

7. Memory Map



*1: For details about USER ROM area, see “User ROM Memory Map For Flash Devices” on the following pages.

*2: For RAMSTART Addresses, see the table on the next page.

*3: Unused GPR banks can be used as RAM area.

GPR: General-Purpose Register

The DMA area is only available if the device contains the corresponding resource.

The available RAM and ROM area depends on the device.

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
82	2B4H	-	-	82	Reserved
83	2B0H	OCU6	Yes	83	Output Compare Unit 6
84	2ACH	OCU7	Yes	84	Output Compare Unit 7
85	2A8H	-	-	85	Reserved
86	2A4H	-	-	86	Reserved
87	2A0H	-	-	87	Reserved
88	29CH	-	-	88	Reserved
89	298H	FRT0	Yes	89	Free-Running Timer 0
90	294H	FRT1	Yes	90	Free-Running Timer 1
91	290H	FRT2	Yes	91	Free-Running Timer 2
92	28CH	-	-	92	Reserved
93	288H	RTC0	No	93	Real Time Clock
94	284H	CAL0	No	94	Clock Calibration Unit
95	280H	-	-	95	Reserved
96	27CH	IIC0	Yes	96	I^2C interface 0
97	278H	IIC1	Yes	97	I^2C interface 1
98	274H	ADC0	Yes	98	A/D Converter 0
99	270H	-	-	99	Reserved
100	26CH	-	-	100	Reserved
101	268H	LINR0	Yes	101	LIN USART 0 RX
102	264H	LINT0	Yes	102	LIN USART 0 TX
103	260H	-	-	103	Reserved
104	25CH	-	-	104	Reserved
105	258H	LINR2	Yes	105	LIN USART 2 RX
106	254H	LINT2	Yes	106	LIN USART 2 TX
107	250H	-	-	107	Reserved
108	24CH	-	-	108	Reserved
109	248H	LINR4	Yes	109	LIN USART 4 RX
110	244H	LINT4	Yes	110	LIN USART 4 TX
111	240H	LINR5	Yes	111	LIN USART 5 RX
112	23CH	LINT5	Yes	112	LIN USART 5 TX
113	238H	-	-	113	Reserved
114	234H	-	-	114	Reserved
115	230H	LINR7	Yes	115	LIN USART 7 RX
116	22CH	LINT7	Yes	116	LIN USART 7 TX
117	228H	-	-	117	Reserved
118	224H	-	-	118	Reserved
119	220H	-	-	119	Reserved
120	21CH	-	-	120	Reserved
121	218H	-	-	121	Reserved
122	214H	-	-	122	Reserved
123	210H	-	-	123	Reserved

12. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

12.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

■Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

■Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

■Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

1. Preventing Over-Voltage and Over-Current Conditions

   Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.
2. Protection of Output Pins

   Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device.
   Therefore, avoid this type of connection.
3. Handling of Unused Input Pins

   Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

■Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
2. Be sure that abnormal current flows do not occur during the power-on sequence.

■Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

■Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

■Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

1. Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.
2. Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
3. Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 MΩ).
   Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.
4. Ground all fixtures and instruments, or protect with anti-static measures.
5. Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.

12.3 Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

1. Humidity

   Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.
2. Discharge of Static Electricity

   When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.
3. Corrosive Gases, Dust, or Oil

   Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.
4. Radiation, Including Cosmic Radiation

   Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.
5. Smoke, Flame

   CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases.

Customers considering the use of Cypress products in other special environmental conditions should consult with sales representatives.

13. Handling Devices

Special care is required for the following when handling the device:

- Latch-up prevention
- Unused pins handling
- External clock usage
- Notes on PLL clock mode operation
- Power supply pins (V_{cc}/V_{ss})
- Crystal oscillator and ceramic resonator circuit
- Turn on sequence of power supply to A/D converter and analog inputs
- Pin handling when not using the A/D converter
- Notes on Power-on
- Stabilization of power supply voltage
- Serial communication
- Mode Pin (MD)

13.1 Latch-up prevention

CMOS IC chips may suffer latch-up under the following conditions:

- A voltage higher than V_{CC} or lower than V_{SS} is applied to an input or output pin.
- A voltage higher than the rated voltage is applied between V_{cc} pins and V_{ss} pins.
- The AV_{CC} power supply is applied before the V_{CC} voltage.

Latch-up may increase the power supply current dramatically, causing thermal damages to the device.

For the same reason, extra care is required to not let the analog power-supply voltage (AV_{CC}, AVRH) exceed the digital power-supply voltage.

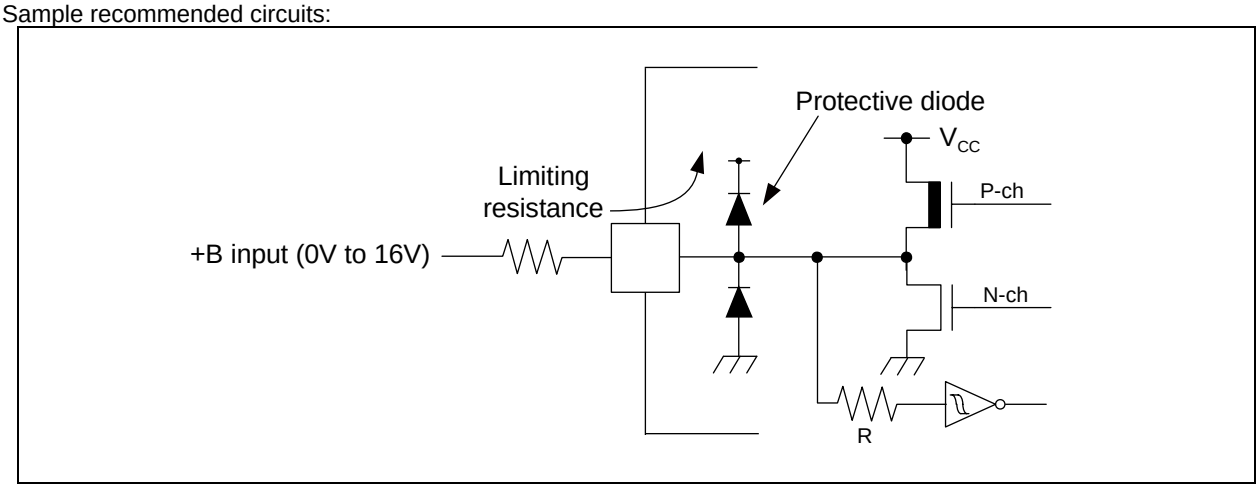
13.2 Unused pins handling

Unused input pins can be left open when the input is disabled (corresponding bit of Port Input Enable register PIER = 0).

Leaving unused input pins open when the input is enabled may result in misbehavior and possible permanent damage of the device. To prevent latch-up, they must therefore be pulled up or pulled down through resistors which should be more than 2kΩ.

Unused bidirectional pins can be set either to the output state and be then left open, or to the input state with either input disabled or external pull-up/pull-down resistor as described above.

- The DEBUG I/F pin has only a protective diode against V_{SS}. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.
- Sample recommended circuits:



*5: The maximum permitted power dissipation depends on the ambient temperature, the air flow velocity and the thermal conductance of the package on the PCB.
The actual power dissipation depends on the customer application and can be calculated as follows:
$P_D = P_{IO} + P_{INT}$
$P_{IO} = \Sigma (V_{OL} \times I_{OL} + V_{OH} \times I_{OH})$ (I/O load power dissipation, sum is performed on all I/O ports)
$P_{INT} = V_{CC} \times (I_{CC} + I_A)$ (internal power dissipation)
I_{CC} is the total core current consumption into V_{CC} as described in the “DC characteristics” and depends on the selected operation mode and clock frequency and the usage of functions like Flash programming.
I_A is the analog current consumption into AV_{CC}.

*6: Worst case value for a package mounted on single layer PCB at specified T_A without air flow.

*7: Write/erase to a large sector in flash memory is warranted with TA ≤ + 105°C.

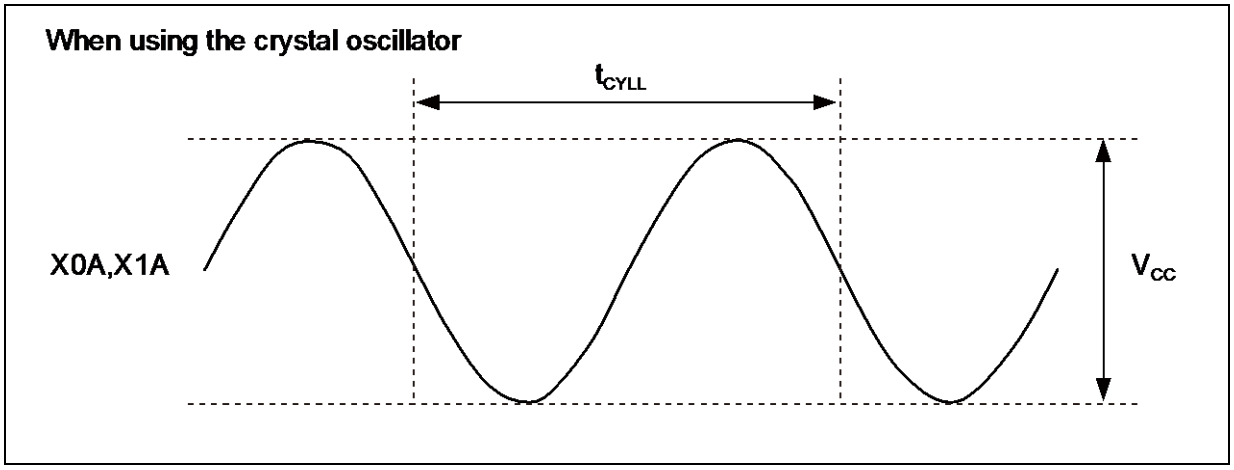
WARNING
Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

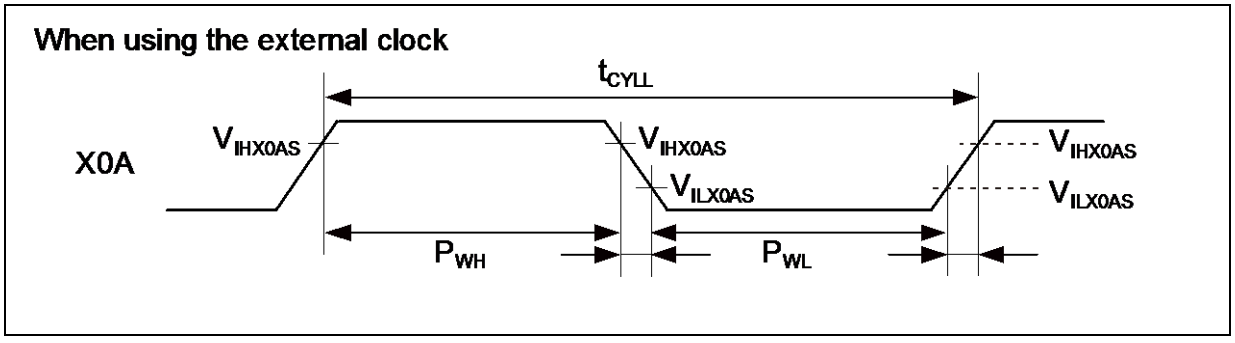
Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Input leak current	I_{IL}	Pnn_m	$V_{SS} < V_I < V_{CC}$ $AV_{SS} < V_I <$ AV_{CC}, AVRH	- 1	-	+ 1	µA	
Pull-up resistance value	R_{PU}	Pnn_m	V_{CC} = 5.0V ±10%	25	50	100	kΩ	
Input capacitance	C_{IN}	Other than C, Vcc, Vss, AVcc, AVss, AVRH	-	-	5	15	pF	

14.4.2 Sub Clock Input Characteristics

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Input frequency	f_{CL}	X0A, X1A	-	-	32.768	-	kHz	When using an oscillation circuit
			-	-	-	100	kHz	When using an opposite phase external clock
		X0A	-	-	-	50	kHz	When using a single phase external clock
Input clock cycle	t_{CYLL}	-	-	10	-	-	µs	
Input clock pulse width	-	-	P_{WH}/t_{CYLL}, P_{WL}/t_{CYLL}	30	-	70	%	





14.4.3 Built-in RC Oscillation Characteristics

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Value			Unit	Remarks
		Min	Typ	Max		
Clock frequency	f_{RC}	50	100	200	kHz	When using slow frequency of RC oscillator
		1	2	4	MHz	When using fast frequency of RC oscillator
RC clock stabilization time	t_{RCSTAB}	80	160	320	µs	When using slow frequency of RC oscillator (16 RC clock cycles)
		64	128	256	µs	When using fast frequency of RC oscillator (256 RC clock cycles)

14.4.4 Internal Clock Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

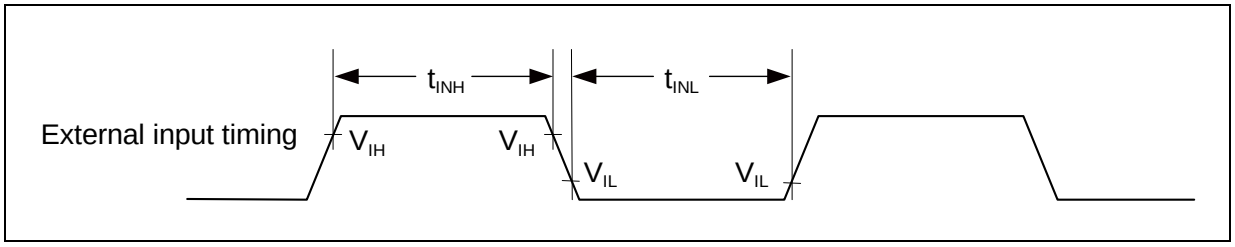
Parameter	Symbol	Value		Unit
		Min	Max	
Internal System clock frequency (CLKS1 and CLKS2)	f_{CLKS1}, f_{CLKS2}	-	54	MHz
Internal CPU clock frequency (CLKB), Internal peripheral clock frequency (CLKP1)	f_{CLKB}, f_{CLKP1}	-	32	MHz
Internal peripheral clock frequency (CLKP2)	f_{CLKP2}	-	32	MHz

14.4.9 External Input Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Value		Unit	Remarks
			Min	Max		
Input pulse width	t_{INH}, t_{INL}	Pnn_m	$2t_{CLKP1}$ +200 (t_{CLKP1}= $1/f_{CLKP1}$)*	-	ns	General Purpose I/O
		ADTG				A/D Converter trigger input
		TINn				Reload Timer
		TTGn				PPG trigger input
		FRCKn, FRCKn_R				Free-Running Timer input clock
		INn, INn_R				Input Capture
		AINn, BINn, ZINn				Quadrature Position/Revolution Counter
		INTn, INTn_R	200	-	ns	External Interrupt
		NMI				Non-Maskable Interrupt

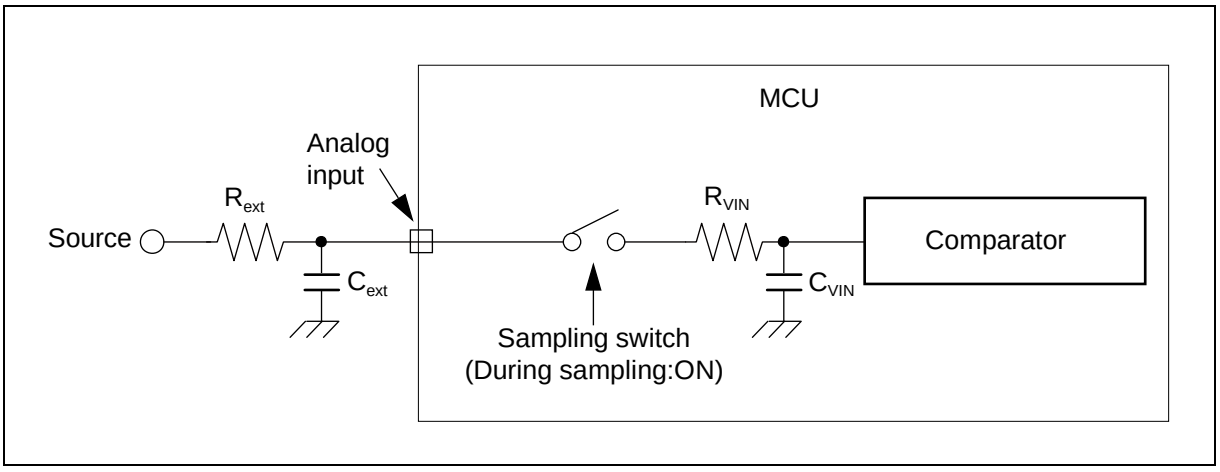
*: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time except stop when in stop mode.



14.5.2 Accuracy and Setting of the A/D Converter Sampling Time

If the external impedance is too high or the sampling time too short, the analog voltage charged to the internal sample and hold capacitor is insufficient, adversely affecting the A/D conversion precision.

To satisfy the A/D conversion precision, a sufficient sampling time must be selected. The required sampling time (Tsamp) depends on the external driving impedance R_{ext}, the board capacitance of the A/D converter input pin C_{ext} and the AV_{CC} voltage level. The following replacement model can be used for the calculation:



R_{ext}: External driving impedance

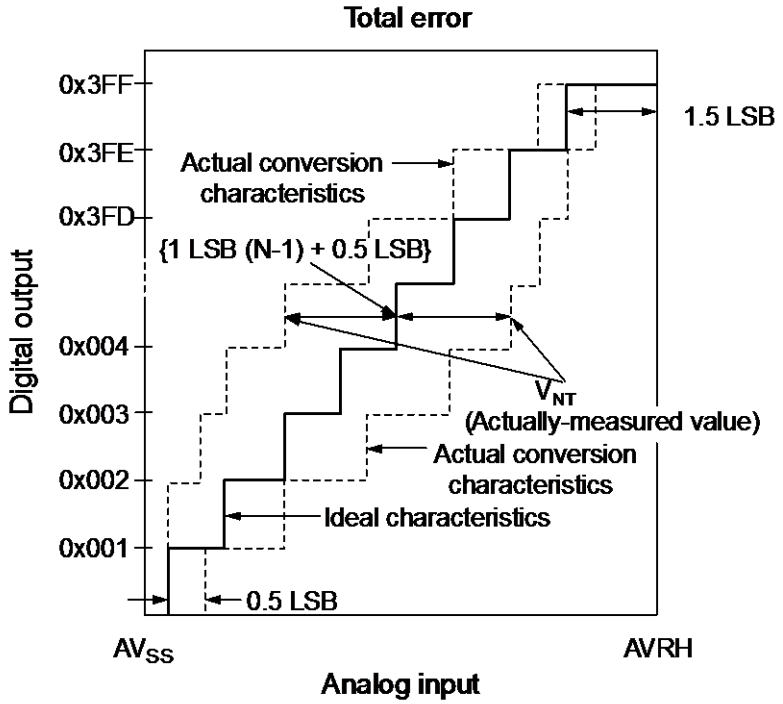
C_{ext}: Capacitance of PCB at A/D converter input

C_{VIN}: Analog input capacity (I/O, analog switch and ADC are contained)

R_{VIN}: Analog input impedance (I/O, analog switch and ADC are contained)

The following approximation formula for the replacement model above can be used:
$Tsamp = 7.62 \times (Rext \times Cext + (Rext + R_{VIN}) \times C_{VIN})$

- Do not select a sampling time below the absolute minimum permitted value.
  ($0.5\mu s$ for $4.5V \le AV_{CC} \le 5.5V$, $1.2\mu s$ for $2.7V \le AV_{CC} < 4.5V$)
- If the sampling time cannot be sufficient, connect a capacitor of about $0.1\mu F$ to the analog input pin.
- A big external driving impedance also adversely affects the A/D conversion precision due to the pin input leakage current IIL (static current before the sampling switch) or the analog input leakage current IAIN (total leakage current of pin input and comparator during sampling). The effect of the pin input leakage current IIL cannot be compensated by an external capacitor.
- The accuracy gets worse as $|AVRH - AV_{SS}|$ becomes smaller.



$$1LSB\ (Ideal\ value) = \frac{AVRH - AV_{SS}}{1024}\ [V]$$

$$Total\ error\ of\ digital\ output\ N = \frac{V_{NT} - \{1LSB \times (N - 1) + 0.5LSB\}}{1LSB}$$

N : A/D converter digital output value.
V_{NT} : Voltage at which the digital output changes from 0x(N + 1) to 0xN.
V_{OT} (Ideal value) = AV_{SS} + 0.5LSB[V]
V_{FST} (Ideal value) = AVRH - 1.5LSB[V]

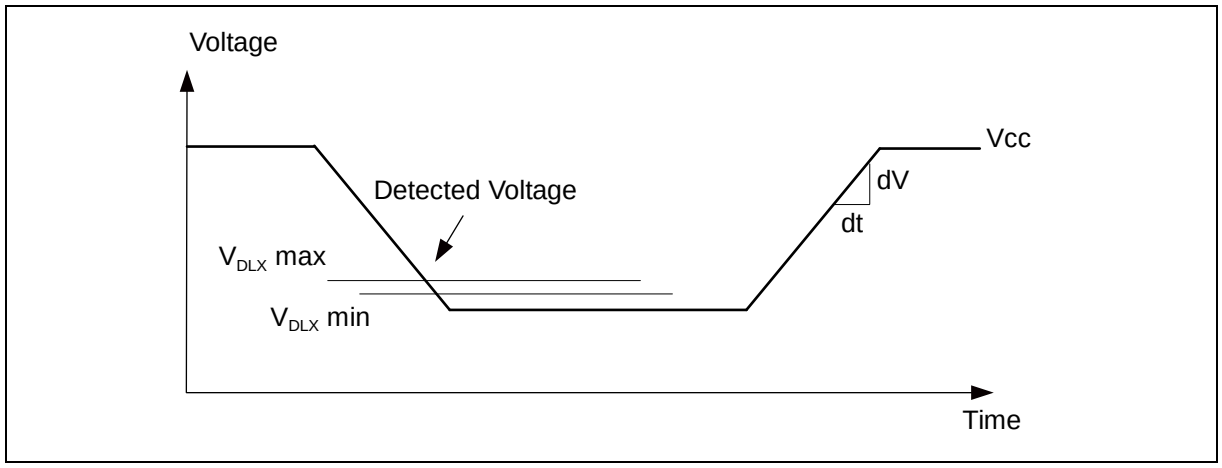
14.6 Low Voltage Detection Function Characteristics

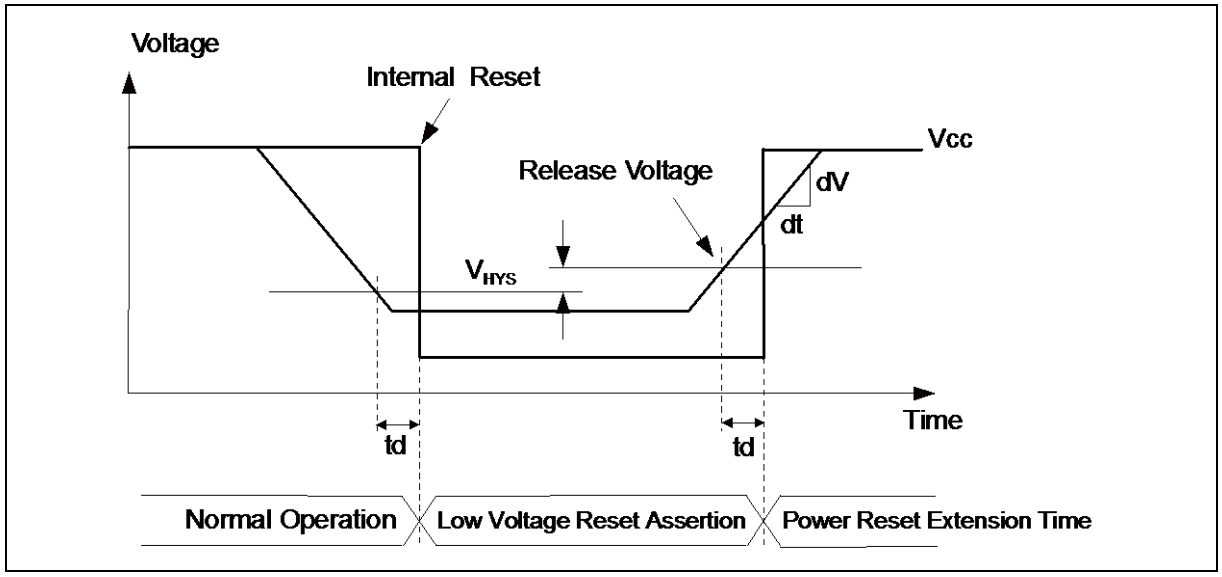
(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

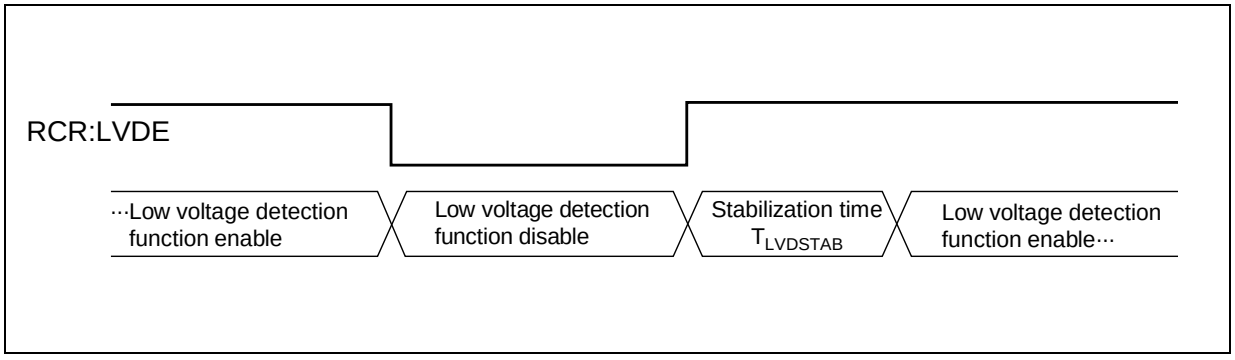
Parameter	Symbol	Conditions	Value			Unit
			Min	Typ	Max	
Detected voltage[*1]	V_{DL0}	CILCR:LVL = 0000_B	2.70	2.90	3.10	V
	V_{DL1}	CILCR:LVL = 0001_B	2.79	3.00	3.21	V
	V_{DL2}	CILCR:LVL = 0010_B	2.98	3.20	3.42	V
	V_{DL3}	CILCR:LVL = 0011_B	3.26	3.50	3.74	V
	V_{DL4}	CILCR:LVL = 0100_B	3.45	3.70	3.95	V
	V_{DL5}	CILCR:LVL = 0111_B	3.73	4.00	4.27	V
	V_{DL6}	CILCR:LVL = 1001_B	3.91	4.20	4.49	V
Power supply voltage change rate[*2]	dV/dt	-	- 0.004	-	+ 0.004	V/µs
Hysteresis width	V_{HYS}	CILCR:LVHYS=0	-	-	50	mV
		CILCR:LVHYS=1	80	100	120	mV
Stabilization time	$T_{LVDSTAB}$	-	-	-	75	µs
Detection delay time	t_d	-	-	-	30	µs

[*1]: If the power supply voltage fluctuates within the time less than the detection delay time (t_d), there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

[*2]: In order to perform the low voltage detection at the detection voltage (V_{DLX}), be sure to suppress fluctuation of the power supply voltage within the limits of the change ration of power supply voltage.


Voltage
Vcc
Detected Voltage
dV
dt
V_{DLX} max
V_{DLX} min
Time


Voltage
Internal Reset
Vcc
Release Voltage
dV
dt
V_{HYS}
Time
td
td
Normal Operation
Low Voltage Reset Assertion
Power Reset Extension Time


RCR:LVDE
···Low voltage detection function enable
Low voltage detection function disable
Stabilization time $T_{LVDSTAB}$
Low voltage detection function enable···

14.7 Flash Memory Write/Erase Characteristics

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter		Conditions	Value			Unit	Remarks
			Min	Typ	Max		
Sector erase time	Large Sector	$T_A \leq$ + 105°C	-	1.6	7.5	s	Includes write time prior to internal erase.
	Small Sector	-	-	0.4	2.1	s	
	Security Sector	-	-	0.31	1.65	s	
Word (16-bit) write time	Large Sector	$T_A \leq$ + 105°C	-	25	400	µs	Not including system-level overhead time.
	Small Sector	-	-	25	400	µs	
Chip erase time		$T_A \leq$ + 105°C	-	11.51	55.05	s	Includes write time prior to internal erase.

Note:

While the Flash memory is written or erased, shutdown of the external power (V_{CC}) is prohibited. In the application system where the external power (V_{CC}) might be shut down while writing or erasing, be sure to turn the power off by using a low voltage detection function.

To put it concrete, change the external power in the range of change ration of power supply voltage (-0.004V/µs to +0.004V/µs) after the external power falls below the detection voltage (V_{DLX})[*1].

Write/Erase cycles and data hold time

Write/Erase cycles (cycle)	Data hold time (year)
1,000	20 [*2]
10,000	10 [*2]
100,000	5 [*2]

[*1]: See "Low Voltage Detection Function Characteristics".

[*2]: This value comes from the technology qualification (using Arrhenius equation to translate high temperature measurements into normalized value at + 85°C).

Page	Section	Change Results
21	Interrupt Vector Table	Changed the Description of CALLV0 to CALLV7 Reserved → CALLV instruction
		Changed the Description of RESET Reserved → Reset vector
		Changed the Description of INT9 Reserved → INT9 instruction
		Changed the Description of EXCEPTION Reserved → Undefined instruction execution
22		Changed the Vector name of Vector number 64 PPGRLT → RLT6
		Changed the Description of Vector number 64 Reload Timer 6 can be used as PPG clock source → Reload Timer 6
25 to 28	Handling Precautions	Added a section
30	Handling Devices	Added the description to “3. External clock usage” (3) Opposite phase external clock
		Changed the description in “7. Turn on sequence of power supply to A/D converter and analog inputs” In this case, the voltage must not exceed AVRH or AV_{CC} → In this case, AVRH must not exceed AV_{CC}. Input voltage for ports shared with analog input ports also must not exceed AV_{CC}
31		Added the description “12. Mode Pin (MD)”
33	Electrical Characteristics 1. Absolute Maximum Ratings	Changed the annotation *4 Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset (except devices with persistent low voltage reset in internal vector mode). → Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.
33	1. Absolute Maximum Ratings	Added the annotation *4 The DEBUG I/F pin has only a protective diode against V_{SS}. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.
35	2. Recommended Operating Conditions	Added the Value and Remarks to “Power supply voltage” Min: 2.0V Typ: - Max: 5.5V Remarks: Maintains RAM data in stop mode
		Changed the Value of “Smoothing capacitor at C pin” Typ: 1.0µF → 1.0µF to 3.9µF Max: 1.5µF → 4.7µF
		Changed the Remarks of “Smoothing capacitor at C pin” Deleted “(Target value)” Added “3.9µF (Allowance within ± 20%)”